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150V N-Channel Enhancement Mode MOSFET

Description

The AP30N15P/T uses advanced **APM-SGT II** technology

to provide excellent $R_{\text{DS}(\text{ON})},$ low gate charge and

operation with gate voltages as low as 4.5V. This

device is suitable for use as a Battery protection

or in other Switching application.

General Features

V_{DS} = 150V I_D = 30A

 $R_{DS(ON)} < 78m\Omega@V_{GS}=10V$ (Type: 63mΩ)

Application

Automative lighting

Load switch

Uninterruptible power supply

Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP30N15P	TO-220-3L	AP30N15P XXX YYYY	1000
AP30N15T	TO-263-3L	AP30N15T XXX YYYY	800

Absolute Maximum Ratings (TC=25 ℃ unless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	150	V
VGS	Gate-Source Voltage	±20	V
I⊳@Tc=25℃	Drain Current, V _{GS} @ 10V	30	А
I₀@Tc=100°C	Drain Current, V _{GS} @ 10V	21	А
IDM	Pulsed Drain Current ¹	90	А
P _D @T _C =25°C	Total Power Dissipation	60	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R0JA Maximum Thermal Resistance, Junctionambient		62.5	°C/W
RθJC	R0JC Maximum Thermal Resistance, Junction-case		°C/W



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Electrical Characteristics@Tj=25°C(unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} = 0V, I _D = 250µA	150	175	-	V
IGSS	Gate-body Leakage current	V_{DS} = 0V, V_{GS} = ±20V	-	-	±100	nA
IDSS	Zero Gate Voltage Drain Current TJ= 25°C	N/ (50)//// 0)/	-	-	1	υA
IDSS	Zero Gate Voltage Drain Current TJ= 100°C	V_{DS} = 150V, V_{GS} = 0V	-	-	100	υA
VGS(th)	Gate-Threshold Voltage	V _{DS} = V _{GS} , I _D = 250µA	2.0	3.0	4.5	V
RDS(on)	Drain-Source On-Resistance ²	V _{GS} = 10V, I _D = 10A	-	63	78	mΩ
RDS(on)	Drain-Source On-Resistance ²	V _{GS} = 4.5V, I _D = 8A		72	90	
gfs	Transconductance	V _{DS} = 5V, I _D = 10A	-	23	-	S
Ciss	Input Capacitance		-	630	-	pF
Coss	Output Capacitance	V _{DS} = 75V, V _{GS} = 0V, f = 1MHz	-	50	-	
Crss	Reverse Transfer Capacitance	1 111112	-	13.5	-	
Rg	Gate Resistance	V _{GS} = 0V, V _{DS} Open, f = 1MHz	-	5	-	Ω
Qg	Total Gate Charge		-	11	-	
Qgs	Gate-Source Charge	V _{GS} = 10V,V _{DD} = 75V, I _D = 10A	-	1.2	-	nC
Qgd	Gate-Drain Charge		-	4	-	
td(on)	Turn-On Delay Time		-	9.8	-	
tr	Rise Time	V _{GS} = 10V, V _{DD} = 75V, R _G	-	6	-	nS
td(off)	Turn-Off Delay Time	= 10Ω, I _D = 10A	-	15	-	115
tf	Fall Time		-	4.1	-	
VSD	Diode Forward Voltage ²	I _S = 10A, V _{GS} = 0V	-	-	1.2	V
trr	Body Diode Reverse Recovery Time	V _R = 75V,I _F = 10A,	-	55	-	nS
Qrr	Body Diode Reverse Recovery Charge	dl/dt= 100A/µs	-	124	-	nC

Note :

1. The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.

2、The data tested by pulsed , pulse width $\leq 300 us$, duty cycle $\leq 2\%$

3、The EAS data shows Max. rating . The test condition is VDD=72V,VGS=10V,L=0.1mH,IAS=13A

4、The power dissipation is limited by 150°C junction temperature

5. The data is theoretically the same as I D and I DM , in real applications , should be limited by total power dissipation.

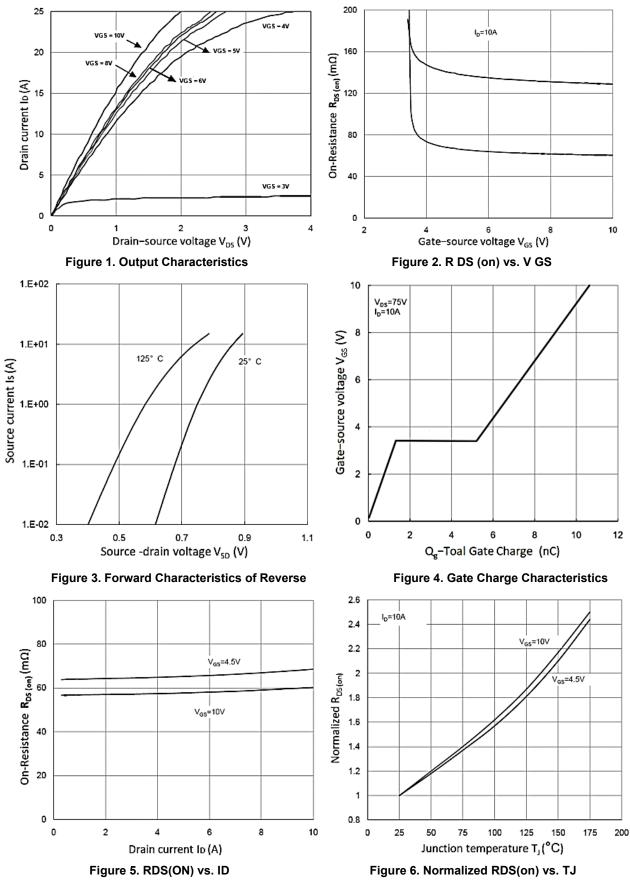
N



<u>AP30N15P/T</u>

150V N-Channel Enhancement Mode MOSFET

Typical Characteristics

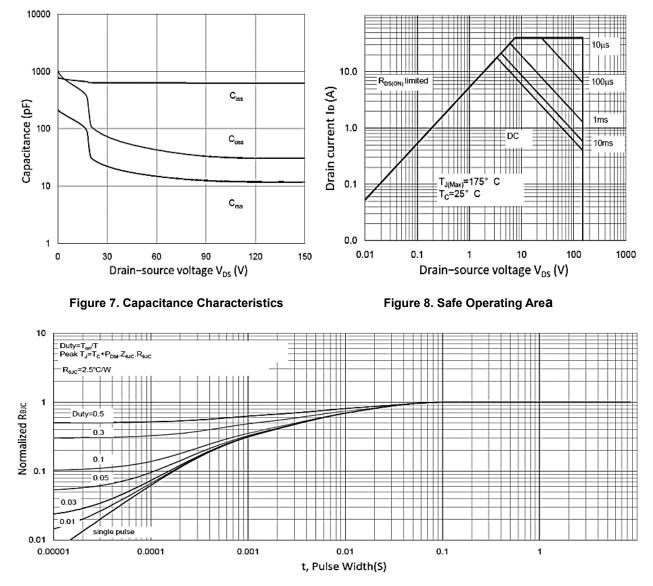


W



<u>AP30N15P/T</u>







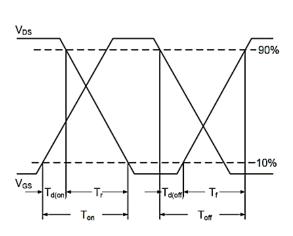


Figure 10. Switching Time Waveform

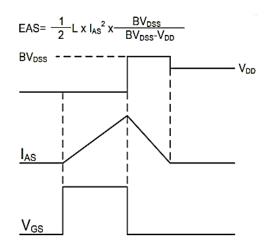
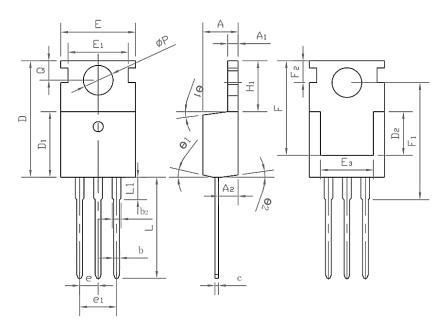


Figure 11. Unclamped Inductive Switching





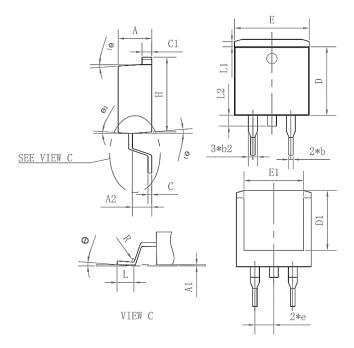
150V N-Channel Enhancement Mode MOSFET Package Mechanical Data-TO-220-3L-SLK



	Common			
Symbol	mm			
-	Mim	Nom	Max	
A	4.27	4.57	4.87	
A1	1.15	1.30	1.45	
A2	2.10	2.40	2.70	
b	0.70	0.80	1.00	
b2	1.17	1.27	1.50	
D	0.40	0.50	0.65	
D1	8.80	9.10	9.40	
D2	5.70	6.70	7.00	
E	9.70	10.00	10.30	
E1	-	8.70	-	
E2	9.63	10.00	10.35	
E3	7.00	8.00	8.40	
e		0.37		
e1		0.10		
H1	6.00	6.50	6.85	
L	12.75	13.50	13.90	
L1	-	3.10	3.40	
Фр	3.45	3.60	3.75	
Q	2.60	2.80	3.00	
θ1	4°	7°	10°	
θ2	0°	3°	6°	
F	13.30	13.50	13.70	
F1	15.50	15.90	16.30	
F2	2.80	3.00	3.20	



150V N-Channel Enhancement Mode MOSFET Package Mechanical Data-TO-263-3L-SLK



		Common		
Symbol	mm			
	Mim	Nom	Max	
A	4.35	4.47	4.60	
A1	0.09	0.10	0.11	
A2	2.30	2.40	2.70	
b	0.70	0.80	1.00	
b2	1.25	1.36	1.50	
С	0.45	0.50	0.65	
C1	1.29	1.30	9.40	
D	9.10	9.20	9.30	
D1	7.90	8.00	8.10	
E	9.85	10.00	10.20	
E1	7.90	8.00	8.10	
Н	15.30	15.50	15.70	
е	-	2.54	-	
L	2.34	2.54	2.74	
L1	1.00	1.10	1.20	
L2	1.30	1.40	1.50	
R	0.24	0.25	0.26	
θ	0°	4°	8°	
Θ1	4°	7°	10°	
Θ2	0°	3°	6°	



<u>AP30N15P/T</u>

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Edition	Date	Change
Rve1.0	2021/10/29	Initial release

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